

## Automotive Grade TFT-LCD Power Supply

The ISL78010 is a multiple output regulator for use in all TFT-LCD automotive applications. It features a single boost converter with an integrated 2A FET, two positive LDOs for  $V_{ON}$  and  $V_{LOGIC}$  generation, and a single negative LDO for  $V_{OFF}$  generation. The boost converter can be programmed to operate in either P-mode for optimal transient response or PI-mode for improved load regulation.

The ISL78010 includes fault protection for all four channels. Once a fault is detected on either the  $V_{BOOST}$ ,  $V_{ON}$  or  $V_{OFF}$  channels, the device is latched off until the input supply or EN is cycled. If a fault is detected on the  $V_{LOGIC}$  channel, the device is latched off until the input supply is cycled. The  $V_{LOGIC}$  channel is not affected by the EN function.

The ISL78010 also includes an integrated start-up sequence for  $V_{LOGIC}$ ,  $V_{BOOST}$ ,  $V_{OFF}$ , then  $V_{ON}$  or for  $V_{LOGIC}$ ,  $V_{OFF}$ ,  $V_{BOOST}$ , and  $V_{ON}$ . The latter sequence requires a single external transistor. The timing of the start-up sequence is set using an external capacitor.

The ISL78010 comes in a 32 Ld 5x5 TQFP package and is specified for operation over a  $-40^{\circ}\text{C}$  to  $+105^{\circ}\text{C}$  temperature range. It is both AEC-Q100 rated and fully TS16949 compliant.

## Ordering Information

PART NUMBER (Notes 1, 2, 3)	PART MARKING	PACKAGE (Pb-free)	PKG. DWG. #
ISL78010ANZ	78010 ANZ	32 Ld 5x5 TQFP	Q32.5x5
ISL78010EVAL1Z	Evaluation Board		

1. Add "-T\*" suffix for tape and reel. Please refer to [TB347](#) for details on reel specifications.
2. These Intersil Pb-free plastic packaged products employ special Pb-free material sets, molding compounds/die attach materials, and 100% matte tin plate plus anneal (e3 termination finish, which is RoHS compliant and compatible with both SnPb and Pb-free soldering operations). Intersil Pb-free products are MSL classified at Pb-free peak reflow temperatures that meet or exceed the Pb-free requirements of IPC/JEDEC J STD-020.
3. For Moisture Sensitivity Level (MSL), please see device information page for [ISL78010](#). For more information on MSL please see techbrief [TB363](#).

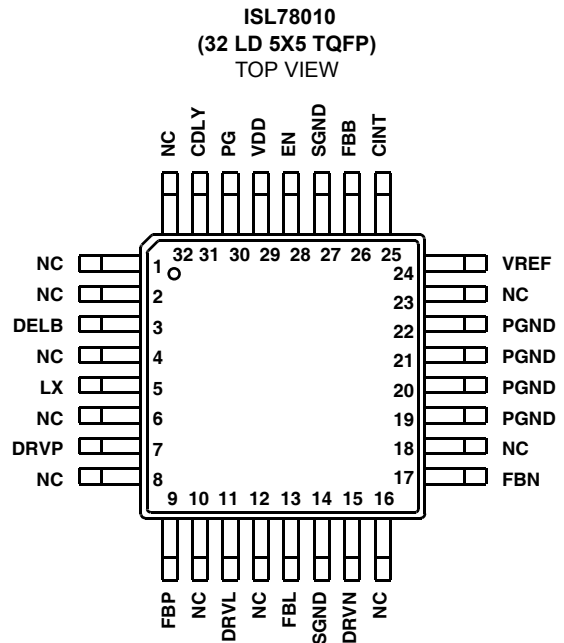
## Features

- 2A current FET
- 3V to 5V input
- Up to 20V boost output
- 1% regulation on boost output
- $V_{LOGIC}$ - $V_{BOOST}$ - $V_{OFF}$ - $V_{ON}$  or  $V_{LOGIC}$ - $V_{OFF}$ - $V_{BOOST}$ - $V_{ON}$  sequence control
- Programmable sequence delay
- Fully fault protected
- Thermal shutdown
- Internal soft-start
- 32 Ld 5x5 TQFP packages
- AEC-Q100 Tested
- TS16949 Compliant
- Pb-free (RoHS compliant)

## Applications

- All Automotive LCD Displays

## Pinout



**Absolute Maximum Ratings** ( $T_A = +25^\circ\text{C}$ )

V <sub>DELB</sub> .....	24V
V <sub>DRVP</sub> .....	36V
V <sub>DRVN</sub> .....	-20V
V <sub>DD</sub> .....	6.5V
V <sub>LX</sub> .....	24V
V <sub>DRVL</sub> .....	6.5V

**Thermal Information**

Thermal Resistance (Typical) (Notes 4, 5) $\Theta_{JA}$ ( $^\circ\text{C}/\text{W}$ )	$\Theta_{JC}$ ( $^\circ\text{C}/\text{W}$ )
32 Ld 5x5 TQFP .....	71 25
Storage Temperature .....	-65 $^\circ\text{C}$ to +150 $^\circ\text{C}$
Power Dissipation .....	see "Typical Performance Curves" (page 5)
Maximum Continuous Junction Temperature .....	+125 $^\circ\text{C}$
Pb-free reflow profile .....	see link below
	<a href="http://www.intersil.com/pbfree/Pb-FreeReflow.asp">http://www.intersil.com/pbfree/Pb-FreeReflow.asp</a>

**Recommended Operating Conditions**

Ambient Operating Temperature .....	-40 $^\circ\text{C}$ to +105 $^\circ\text{C}$
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**CAUTION:** Do not operate at or near the maximum ratings listed for extended periods of time. Exposure to such conditions may adversely impact product reliability and result in failures not covered by warranty.

**NOTE:**

- $\Theta_{JA}$  is measured with the component mounted on a high effective thermal conductivity test board in free air. See Tech Brief [TB379](#) for details.
- For  $\Theta_{JC}$ , the "case temp" location is taken at the package top center.

**IMPORTANT NOTE:** All parameters having Min/Max specifications are guaranteed. Typical values are for information purposes only. Unless otherwise noted, all tests are at the specified temperature and are pulsed tests, therefore:  $T_J = T_C = T_A$ .

**Electrical Specifications**  $V_{DD} = 5\text{V}$ ,  $V_{BOOST} = 11\text{V}$ ,  $I_{LOAD} = 200\text{mA}$ ,  $V_{ON} = 15\text{V}$ ,  $V_{OFF} = -5\text{V}$ ,  $V_{LOGIC} = 2.5\text{V}$ , limits over -40 $^\circ\text{C}$  to +105 $^\circ\text{C}$  temperature range, unless otherwise specified. **Boldface limits apply over the operating temperature range, -40 $^\circ\text{C}$  to +105 $^\circ\text{C}$ .**

PARAMETER	DESCRIPTION	CONDITION	MIN (Note 6)	TYP	MAX (Note 6)	UNIT
<b>SUPPLY</b>						
V <sub>S</sub>	Supply Voltage		<b>3</b>		<b>5.5</b>	V
I <sub>S</sub>	Quiescent Current	Enabled, LX not switching		1.7	<b>2.5</b>	mA
		Disabled		750	<b>900</b>	$\mu\text{A}$
<b>CLOCK</b>						
f <sub>OSC</sub>	Oscillator Frequency		<b>900</b>	1000	<b>1100</b>	kHz
<b>BOOST</b>						
V <sub>BOOST</sub>	Boost Output Range		<b>5.5</b>		<b>20</b>	V
V <sub>FBB</sub>	Boost Feedback Voltage	T <sub>A</sub> = +25 $^\circ\text{C}$	1.192	1.205	1.218	V
			<b>1.188</b>	1.205	<b>1.222</b>	V
V <sub>F_FBB</sub>	FBB Fault Trip Point			0.9		V
V <sub>REF</sub>	Reference Voltage	T <sub>A</sub> = +25 $^\circ\text{C}$	1.19	1.215	1.235	V
			<b>1.187</b>	1.215	<b>1.238</b>	V
D <sub>MAX</sub>	Maximum Duty Cycle		<b>85</b>			%
I <sub>LXMAX</sub>	Current Switch			2.0		A
I <sub>LEAK</sub>	Switch Leakage Current	V <sub>LX</sub> = 16V			<b>10</b>	$\mu\text{A}$
r <sub>DS(ON)</sub>	Switch ON-Resistance			320		m $\Omega$
Eff	Boost Efficiency	See "Typical Performance Curves" (page 5)	<b>85</b>	92		%
I(V <sub>FBB</sub> )	Feedback Input Bias Current	PI mode, V <sub>FBB</sub> = 1.35V		50	<b>500</b>	nA
$\Delta V_{BOOST}/\Delta V_{IN}$	Line Regulation	C <sub>INT</sub> = 4.7nF, I <sub>OUT</sub> = 100mA, V <sub>IN</sub> = 3V to 5.5V		0.05		%/V
$\Delta V_{BOOST}/\Delta I_{BOOST}$	Load Regulation - "P" Mode	C <sub>INT</sub> pin strapped to V <sub>DD</sub> , 50mA < I <sub>LOAD</sub> < 250mA		3		%
$\Delta V_{BOOST}/\Delta I_{BOOST}$	Load Regulation - "PI" Mode	C <sub>INT</sub> = 4.7nF, 50mA < I <sub>O</sub> < 250mA		0.1		%

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**Electrical Specifications**  $V_{DD} = 5V$ ,  $V_{BOOST} = 11V$ ,  $I_{LOAD} = 200mA$ ,  $V_{ON} = 15V$ ,  $V_{OFF} = -5V$ ,  $V_{LOGIC} = 2.5V$ , limits over  $-40^{\circ}C$  to  $+105^{\circ}C$  temperature range, unless otherwise specified. **Boldface limits apply over the operating temperature range,  $-40^{\circ}C$  to  $+105^{\circ}C$ .** (Continued)

PARAMETER	DESCRIPTION	CONDITION	MIN (Note 6)	TYP	MAX (Note 6)	UNIT
V <sub>CINT_T</sub>	CINT PI Mode Select Threshold			4.7	<b>4.8</b>	V
<b>V<sub>ON</sub> LDO</b>						
V <sub>FBP</sub>	FBP Regulation Voltage	I <sub>DRVP</sub> = 0.2mA, T <sub>A</sub> = +25°C	1.176	1.2	1.224	V
		I <sub>DRVP</sub> = 0.2mA	<b>1.172</b>	1.2	<b>1.228</b>	V
V <sub>F_FBP</sub>	FBP Fault Trip Point	V <sub>FBP</sub> falling	<b>0.82</b>	0.87	<b>0.92</b>	V
I <sub>FBP</sub>	FBP Input Bias Current	V <sub>FBP</sub> = 1.35V	<b>-250</b>		<b>250</b>	nA
G <sub>MP</sub>	FBP Effective Transconductance	V <sub>DRVP</sub> = 25V, I <sub>DRVP</sub> = 0.2mA to 2mA		50		ms
$\Delta V_{ON}/\Delta I(V_{ON})$	V <sub>ON</sub> Load Regulation	I(V <sub>ON</sub> ) = 0mA to 20mA		-0.5		%
I <sub>DRVP</sub>	DRVP Sink Current Max	V <sub>FBP</sub> = 1.1V, V <sub>DRVP</sub> = 25V	<b>2</b>	4		mA
I <sub>L_DRVP</sub>	DRVP Leakage Current	V <sub>FBP</sub> = 1.5V, V <sub>DRVP</sub> = 35V		0.1	<b>5</b>	μA
<b>V<sub>OFF</sub> LDO</b>						
V <sub>FBN</sub>	FBN Regulation Voltage	I <sub>DRVN</sub> = 0.2mA, T <sub>A</sub> = +25°C	0.173	0.203	0.233	V
		I <sub>DRVN</sub> = 0.2mA	<b>0.171</b>	0.203	<b>0.235</b>	V
V <sub>F_FBN</sub>	FBN Fault Trip Point	V <sub>FBN</sub> falling	<b>0.38</b>	0.43	<b>0.48</b>	V
I <sub>FBN</sub>	FBN Input Bias Current	V <sub>FBN</sub> = 0.2V	<b>-250</b>		<b>250</b>	nA
G <sub>MN</sub>	FBN Effective Transconductance	V <sub>DRVN</sub> = -6V, I <sub>DRVN</sub> = 0.2mA to 2mA		50		mS
$\Delta V_{OFF}/\Delta I(V_{OFF})$	V <sub>OFF</sub> Load Regulation	I(V <sub>OFF</sub> ) = 0mA to 20mA		-0.5		%
I <sub>DRVN</sub>	DRVN Source Current Max	V <sub>FBN</sub> = 0.3V, V <sub>DRVN</sub> = -6V	<b>2</b>	4		mA
I <sub>L_DRVN</sub>	DRVN Leakage Current	V <sub>FBN</sub> = 0V, V <sub>DRVN</sub> = -20V		0.1	<b>5</b>	μA
<b>V<sub>LOGIC</sub> LDO</b>						
V <sub>FBL</sub>	FBL Regulation Voltage	I <sub>DRVL</sub> = 1mA, T <sub>A</sub> = +25°C	1.176	1.2	1.224	V
		I <sub>DRVL</sub> = 1mA	<b>1.174</b>	1.2	<b>1.226</b>	V
V <sub>F_FBL</sub>	FBL Fault Trip Point	V <sub>FBL</sub> falling	<b>0.82</b>	0.87	<b>0.92</b>	V
I <sub>FBL</sub>	FBL Input Bias Current	V <sub>FBL</sub> = 1.35V	<b>-500</b>		<b>500</b>	nA
G <sub>ML</sub>	FBL Effective Transconductance	V <sub>DRVL</sub> = 2.5V, I <sub>DRVL</sub> = 1mA to 8mA		200		mS
$\Delta V_{LOGIC}/\Delta I(V_{LOGIC})$	V <sub>LOGIC</sub> Load Regulation	I(V <sub>LOGIC</sub> ) = 100mA to 500mA		0.5		%
I <sub>DRVL</sub>	DRVL Sink Current Max	V <sub>FBL</sub> = 1.1V, V <sub>DRVL</sub> = 2.5V	<b>8</b>	16		mA
I <sub>L_DRL</sub>	I <sub>L_DRVL</sub>	V <sub>FBL</sub> = 1.5V, V <sub>DRVL</sub> = 5.5V		0.1	<b>5</b>	μA
<b>SEQUENCING</b>						
t <sub>ON</sub>	Turn On Delay	C <sub>DLY</sub> = 0.22μF		30		ms
t <sub>SS</sub>	Soft-start Time	C <sub>DLY</sub> = 0.22μF		2		ms
t <sub>DEL1</sub>	Delay Between A <sub>VDD</sub> and V <sub>OFF</sub>	C <sub>DLY</sub> = 0.22μF		10		ms
t <sub>DEL2</sub>	Delay Between V <sub>ON</sub> and V <sub>OFF</sub>	C <sub>DLY</sub> = 0.22μF		17		ms
I <sub>DELB</sub>	DELB Pull-down Current	V <sub>DELB</sub> > 0.6V		50		μA
		V <sub>DELB</sub> < 0.6V		1.4		mA

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**Electrical Specifications**  $V_{DD} = 5V$ ,  $V_{BOOST} = 11V$ ,  $I_{LOAD} = 200mA$ ,  $V_{ON} = 15V$ ,  $V_{OFF} = -5V$ ,  $V_{LOGIC} = 2.5V$ , limits over  $-40^{\circ}C$  to  $+105^{\circ}C$  temperature range, unless otherwise specified. **Boldface limits apply over the operating temperature range,  $-40^{\circ}C$  to  $+105^{\circ}C$ .** (Continued)

PARAMETER	DESCRIPTION	CONDITION	MIN (Note 6)	TYP	MAX (Note 6)	UNIT
<b>FAULT DETECTION</b>						
$t_{FAULT}$	Fault Time Out	$C_{DLY} = 0.22\mu F$		50		ms
OT	Over-temperature Threshold			140		$^{\circ}C$
$I_{PG}$	PG Pull-down Current	$V_{PG} > 0.6V$		15		$\mu A$
		$V_{PG} < 0.6V$		1.7		mA
<b>LOGIC ENABLE</b>						
$V_{HI}$	Logic High Threshold		<b>2.3</b>			V
$V_{LO}$	Logic Low Threshold				<b>0.8</b>	V
$I_{LOW}$	Logic Low Bias Current			0.2	<b>2</b>	$\mu A$
$I_{HIGH}$	Logic High Bias Current	at $V_{EN} = 5V$	<b>12</b>	18	<b>24</b>	$\mu A$

**NOTE:**

6. Parameters with MIN and/or MAX limits are 100% tested at  $+25^{\circ}C$ , unless otherwise specified. Temperature limits established by characterization and are not production tested.

## Pin Descriptions

PIN NAME	PIN NUMBER	DESCRIPTION
1, 2, 4, 6, 8, 10, 12, 16, 18, 23, 32	NC	Not connected
3	DELB	Open drain output for gate drive of optional $V_{BOOST}$ delay FET
5	LX	Drain of the internal N-Channel boost FET
7	DRVP	Positive LDO base drive; open drain of an internal N-Channel FET
9	FBP	Positive LDO voltage feedback input pin; regulates to 1.2V nominal
11	DRVL	Logic LDO base drive; open drain of an internal N-Channel FET
13	FBL	Logic LDO voltage feedback input pin; regulates to 1.2V nominal
14, 27	SGND	Low noise signal ground
15	DRVN	Negative LDO base drive; open drain of an internal P-Channel FET
17	FBN	Negative LDO voltage feedback input pin; regulates to 0.2V nominal
19, 20, 21, 22	PGND	Power ground, connected to source of internal N-Channel boost FET
24	VREF	Bandgap reference output voltage; bypass with a $0.1\mu F$ to SGND
25	CINT	$V_{BOOST}$ integrator output; connect capacitor to SGND for PI-mode or connect to $V_{DD}$ for P-mode operation
26	FBB	Boost regulator voltage feedback input pin; regulates to 1.2V nominal
28	EN	Enable pin; High = Enable; Low or floating = Disable
29	VDD	Positive supply
30	PG	Push-pull gate drive of optional fault protection FET; when chip is disabled or when a fault has been detected, this is high
31	CDLY	A capacitor connected from this pin to SGND sets the delay time for start-up sequence and sets the fault timeout time

Typical Performance Curves

$T_A = +25^\circ\text{C}$ , unless otherwise specified.

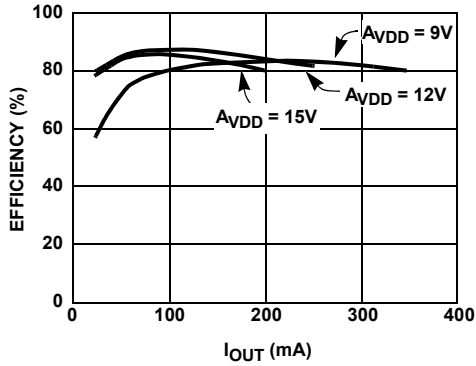


FIGURE 1.  $V_{\text{BOOST}}$  EFFICIENCY AT  $V_{\text{IN}} = 3\text{V}$  (PI-MODE)

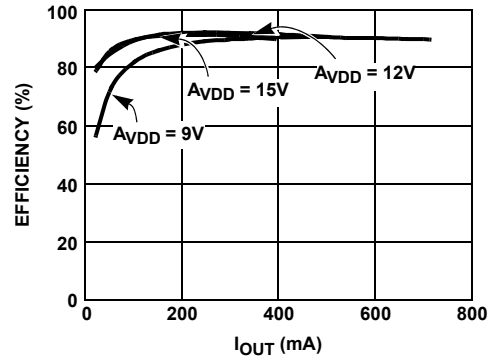


FIGURE 2.  $V_{\text{BOOST}}$  EFFICIENCY AT  $V_{\text{IN}} = 5\text{V}$  (PI-MODE)

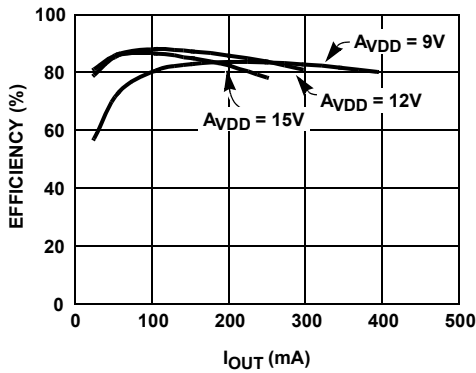


FIGURE 3.  $V_{\text{BOOST}}$  EFFICIENCY AT  $V_{\text{IN}} = 3\text{V}$  (P-MODE)

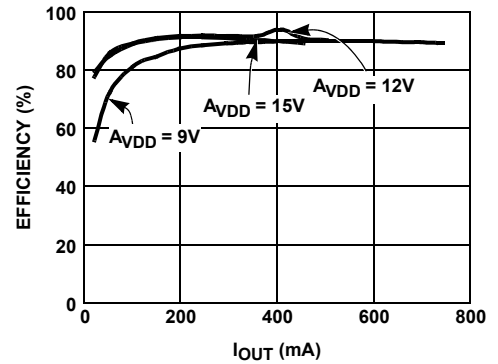


FIGURE 4.  $V_{\text{BOOST}}$  EFFICIENCY AT  $V_{\text{IN}} = 5\text{V}$  (P-MODE)

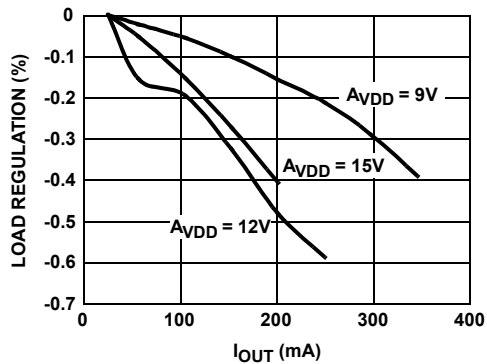


FIGURE 5.  $V_{\text{BOOST}}$  LOAD REGULATION AT  $V_{\text{IN}} = 3\text{V}$  (PI-MODE)

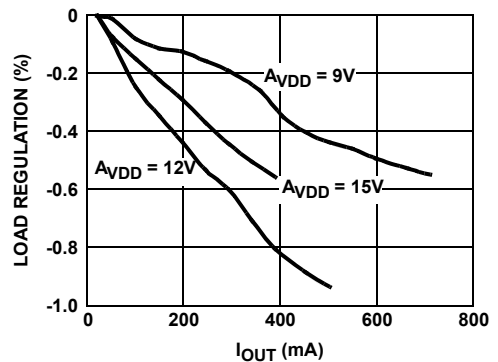


FIGURE 6.  $V_{\text{BOOST}}$  LOAD REGULATION AT  $V_{\text{IN}} = 5\text{V}$  (PI-MODE)

Typical Performance Curves

$T_A = +25^\circ\text{C}$ , unless otherwise specified. (Continued)

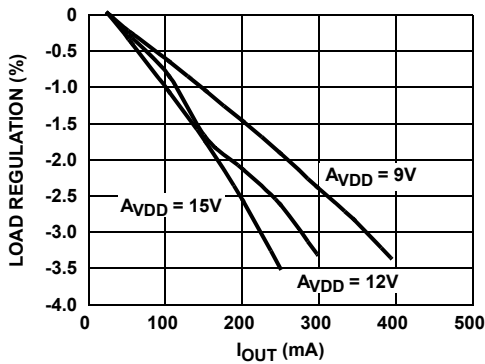


FIGURE 7.  $V_{\text{BOOST}}$  LOAD REGULATION AT  $V_{\text{IN}} = 3\text{V}$  (P-MODE)

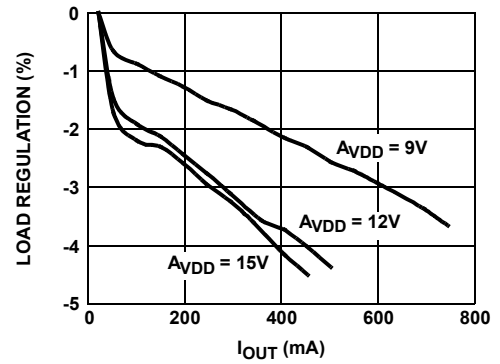


FIGURE 8.  $V_{\text{BOOST}}$  LOAD REGULATION AT  $V_{\text{IN}} = 5\text{V}$  (P-MODE)

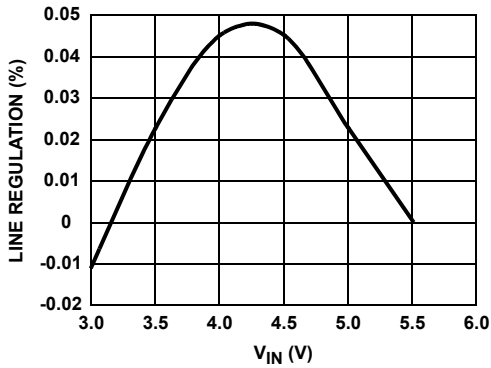


FIGURE 9.  $V_{\text{BOOST}}$  LINE REGULATION (PI-MODE)

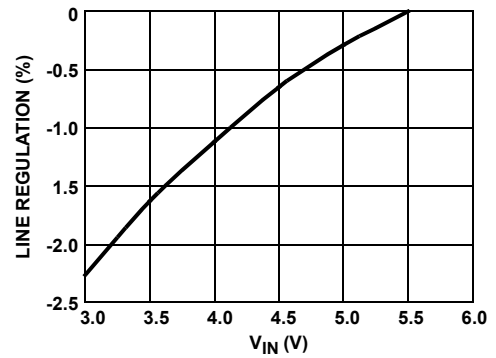


FIGURE 10.  $V_{\text{BOOST}}$  LINE REGULATION (P-MODE)

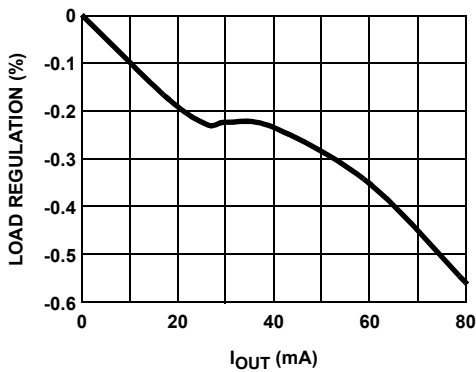


FIGURE 11.  $V_{\text{ON}}$  LOAD REGULATION

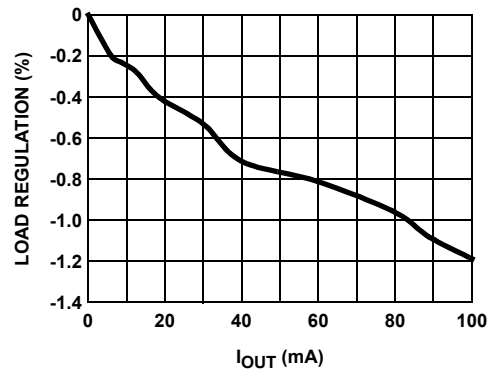


FIGURE 12.  $V_{\text{OFF}}$  LOAD REGULATION

Typical Performance Curves

T<sub>A</sub> = +25°C, unless otherwise specified. (Continued)

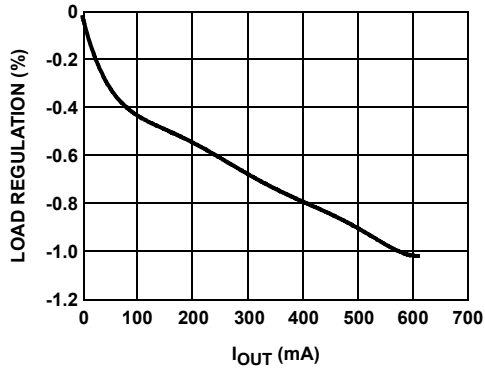


FIGURE 13. V<sub>LOGIC</sub> LOAD REGULATION

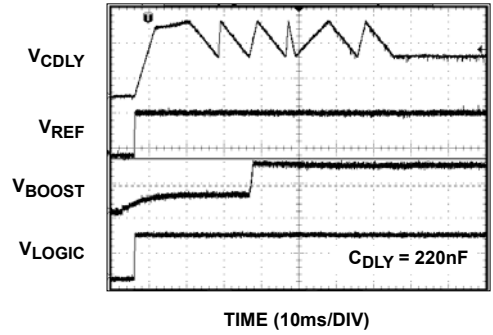


FIGURE 14. START-UP SEQUENCE

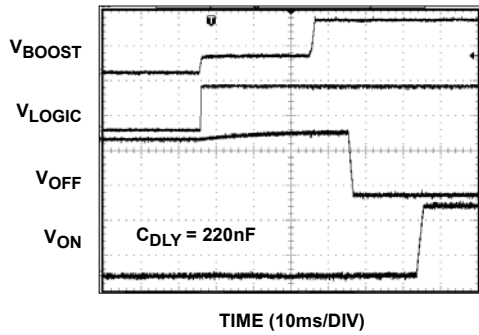


FIGURE 15. START-UP SEQUENCE

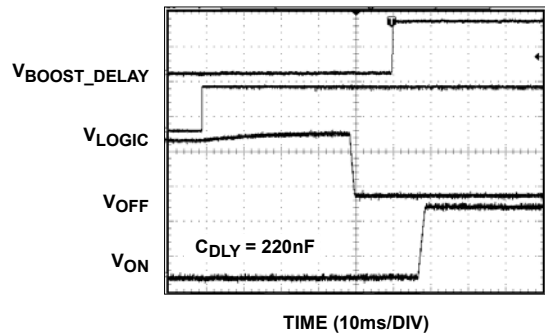


FIGURE 16. START-UP SEQUENCE

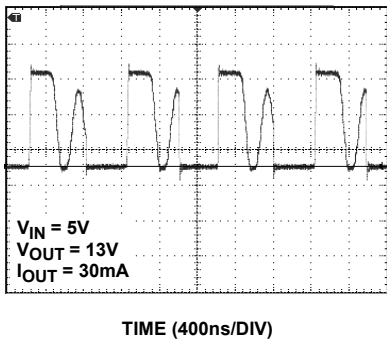


FIGURE 17. LX WAVEFORM - DISCONTINUOUS MODE

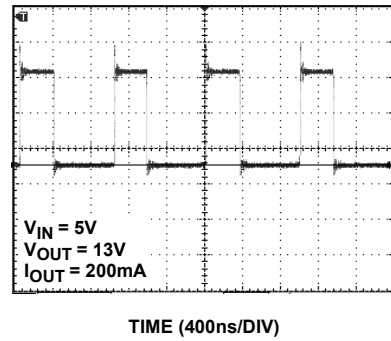


FIGURE 18. LX WAVEFORM - CONTINUOUS MODE

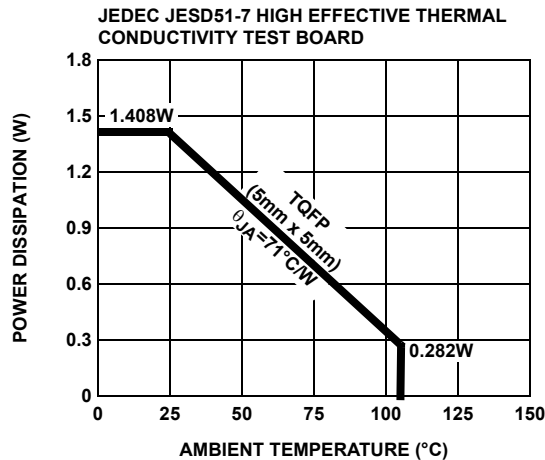


FIGURE 19. PACKAGE POWER DISSIPATION vs AMBIENT TEMPERATURE

## Applications Information

The ISL78010 provides a highly integrated multiple output power solution for TFT-LCD automotive applications. The system consists of one high efficiency boost converter and three linear-regulator controllers ( $V_{ON}$ ,  $V_{OFF}$ , and  $V_{LOGIC}$ ) with multiple protection functions. A block diagram is shown in Figure 20. Table 1 lists the recommended components.

The ISL78010 integrates an N-Channel MOSFET boost converter to minimize external component count and cost. The  $A_{VDD}$ ,  $V_{ON}$ ,  $V_{OFF}$ , and  $V_{LOGIC}$  output voltages are independently set using external resistors.  $V_{ON}$ ,  $V_{OFF}$  voltages require external charge pumps which are post regulated using the integrated LDO controllers.

**TABLE 1. RECOMMENDED TYPICAL APPLICATION DIAGRAM COMPONENTS**

DESIGNATION	DESCRIPTION
C <sub>1</sub> , C <sub>2</sub> , C <sub>3</sub>	10 $\mu$ F, 16V X7R ceramic capacitor (1206) TDK C3216X7R1C106M
C <sub>20</sub> , C <sub>31</sub>	4.7 $\mu$ F, 25V X5R ceramic capacitor (1206) TDK C3216X5R1A475K
D <sub>1</sub>	1A, 20V low leakage Schottky rectifier (CASE 457-04) ON SEMI MBRM120ET3
D <sub>11</sub> , D <sub>12</sub> , D <sub>21</sub>	200mA, 30V Schottky barrier diode (SOT-23) Fairchild BAT54S
L <sub>1</sub>	6.8 $\mu$ H, 1.3A Inductor TDK SLF6025T-6R8M1R3-PF
Q <sub>1</sub>	-2.4, -20V P-Channel 1.8V specified PowerTrench MOSFET (SuperSOT-3) Fairchild FDN304P
Q <sub>2</sub>	200mA, 40V NPN amplifier (SOT-23) Fairchild MMBT3904
Q <sub>3</sub>	200mA, 40V PNP amplifier (SOT-23) Fairchild MMBT3906
Q <sub>4</sub>	-2A, -30V single P-Channel logic level PowerTrench MOSFET (SuperSOT-3) Fairchild FDN360P
Q <sub>5</sub>	1A, 30V PNP low saturation amplifier (SOT-23) Fairchild FM549

## Boost Converter

The main boost converter is a current mode PWM converter at a fixed frequency of 1MHz, which enables the use of low profile inductors and multi-layer ceramic capacitors. This results in a compact, low cost power system for LCD panel design.

The ISL78010 is designed for continuous current mode, but it can also operate in discontinuous current mode at light load. In continuous current mode, current flows continuously in the inductor during the entire switching cycle in steady state operation. The voltage conversion ratio in continuous current mode is given by Equation 1:

$$\frac{A_{VDD}}{V_{IN}} = \frac{1}{1-D} \quad (\text{EQ. 1})$$

where D is the duty cycle of the switching MOSFET.

Figure 21 shows the block diagram of the boost regulator. It uses a summing amplifier architecture consisting of GM stages for voltage feedback, current feedback and slope compensation. A comparator looks at the peak inductor current cycle by cycle and terminates the PWM cycle if the current limit is reached.

An external resistor divider is required to divide the output voltage down to the nominal reference voltage. Current drawn by the resistor network should be limited to maintain the overall converter efficiency. The maximum value of the resistor network is limited by the feedback input bias current and the potential for noise being coupled into the feedback pin. A resistor network in the order of 60k $\Omega$  is recommended. The boost converter output voltage is determined by Equation 2:

$$A_{VDD} = \frac{R_1 + R_2}{R_1} \times V_{REF} \quad (\text{EQ. 2})$$

The current through the MOSFET is limited to 2A peak. This restricts the maximum output current based on Equation 3:

$$I_{OMAX} = \left( I_{LMT} - \frac{\Delta I_L}{2} \right) \times \frac{V_{IN}}{V_O} \quad (\text{EQ. 3})$$

Where  $\Delta I_L$  is peak to peak inductor ripple current, and is set by Equation 4:

$$\Delta I_L = \frac{V_{IN}}{L} \times \frac{D}{f_S} \quad (\text{EQ. 4})$$

where  $f_S$  is the switching frequency.



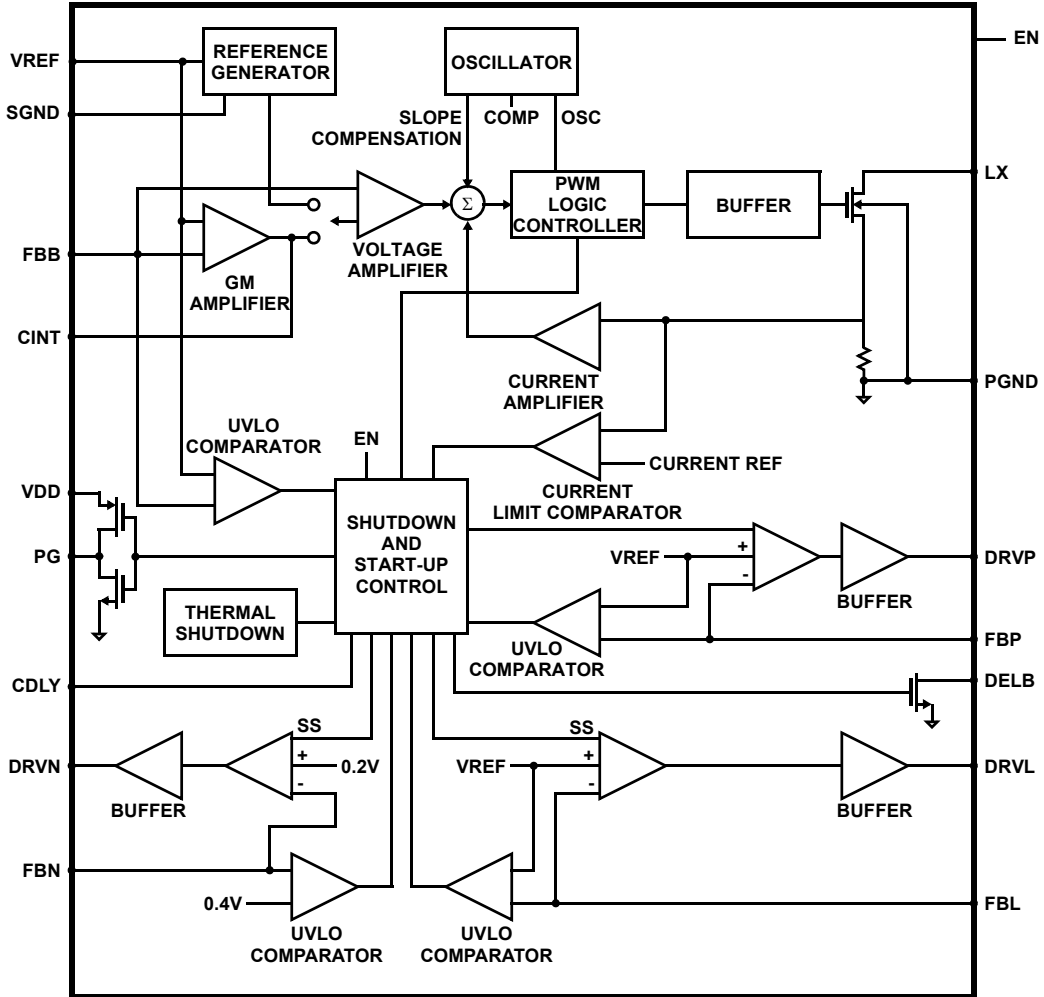


FIGURE 20. BLOCK DIAGRAM

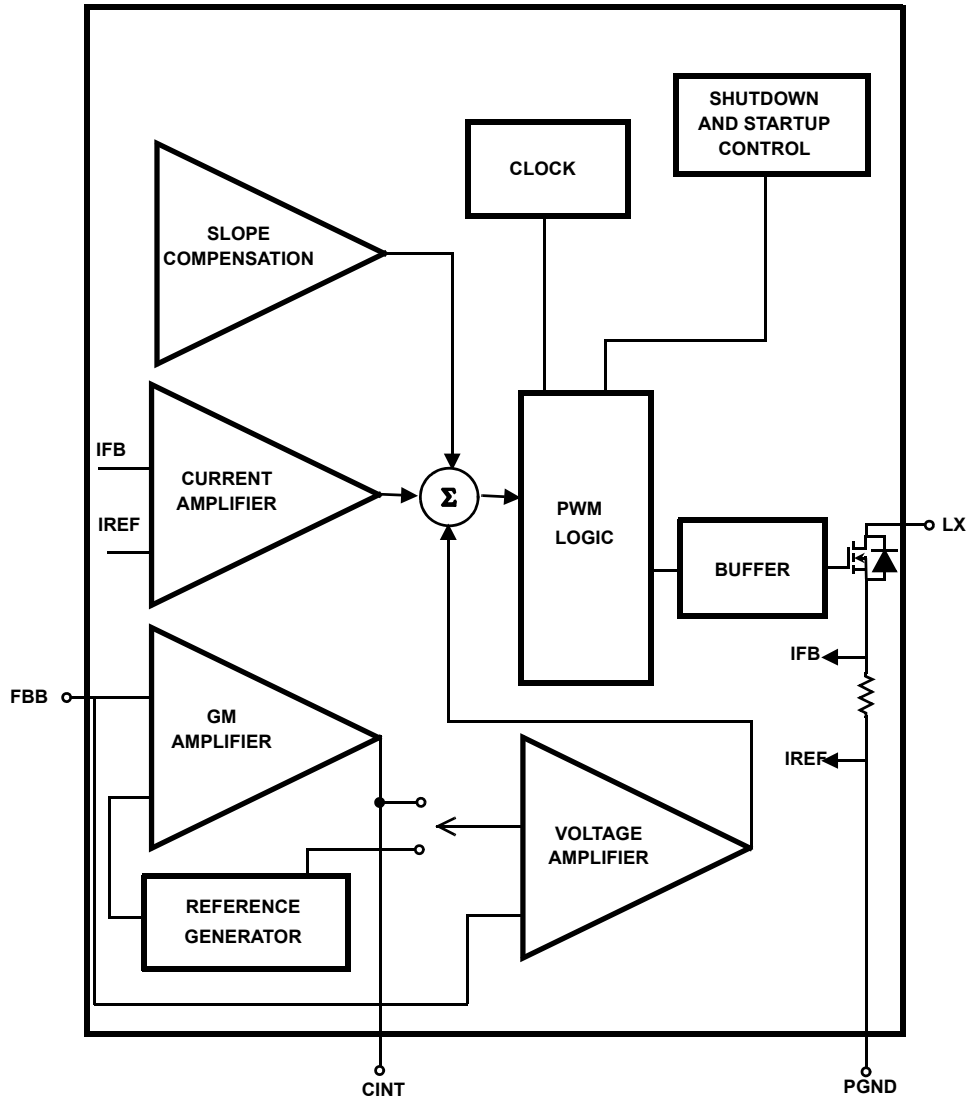


FIGURE 21. BLOCK DIAGRAM OF THE BOOST REGULATOR

Table 2 gives typical values (margins are considered 10%, 3%, 20%, 10%, and 15%) on  $V_{IN}$ ,  $V_O$ ,  $L$ ,  $f_S$ , and  $I_{OMAX}$ .

TABLE 2. TYPICAL  $V_{IN}$ ,  $V_O$ ,  $L$ ,  $f_S$ , AND  $I_{OMAX}$  VALUES

$V_{IN}$ (V)	$V_O$ (V)	$L$ ( $\mu$ H)	$f_S$ (MHz)	$I_{OMAX}$ (A)
3.3	9	6.8	1	0.490686
3.3	12	6.8	1	0.307353
3.3	15	6.8	1	0.197353
5	9	6.8	1	0.743464
5	12	6.8	1	0.465686
5	15	6.8	1	0.29902

### Input Capacitor

An input capacitor is used to supply the peak charging current to the converter. It is recommended that  $C_{IN}$  be larger than  $10\mu$ F. The reflected ripple voltage will be smaller with larger  $C_{IN}$ . The voltage rating of the input capacitor should be larger than the maximum input voltage.

### Boost Inductor

The boost inductor is a critical part which influences the output voltage ripple, transient response, and efficiency. Values of  $3.3\mu$ H to  $10\mu$ H are to match the internal slope compensation. The inductor must be able to handle the following average (Equation 5) and peak (Equation 6) current:

$$I_{LAVG} = \frac{I_O}{1-D} \quad (\text{EQ. 5})$$

$$I_{LPK} = I_{LAVG} + \frac{\Delta I_L}{2} \quad (\text{EQ. 6})$$

### Rectifier Diode

A high-speed diode is necessary due to the high switching frequency. Schottky diodes are recommended because of their fast recovery time and low forward voltage. The rectifier diode must meet the output current and peak inductor current requirements.

### Output Capacitor

The output capacitor supplies the load directly and reduces the ripple voltage at the output. Output ripple voltage consists of two components: the voltage drop due to the inductor ripple current flowing through the ESR of output capacitor, and the charging and discharging of the output capacitor (Equation 7).

$$V_{RIPPLE} = I_{LPK} \times ESR + \frac{V_O - V_{IN}}{V_O} \times \frac{I_O}{C_{OUT}} \times \frac{1}{f_S} \quad (\text{EQ. 7})$$

For low ESR ceramic capacitors, the output ripple is dominated by the charging and discharging of the output

capacitor. The voltage rating of the output capacitor should be greater than the maximum output voltage.

NOTE: Capacitors have a voltage coefficient that makes their effective capacitance drop as the voltage across them increases.  $C_{OUT}$  in Equation 7 assumes the effective value of the capacitor at a particular voltage and not the manufacturer's stated value, measured at zero volts.

### Compensation

The ISL78010 can operate in either P-mode or PI-mode. P-mode may be preferred in applications where excellent transient load performance is required but regulation is not critical. Connecting the CINT pin directly to  $V_{IN}$  will enable P-mode; for better load regulation, use PI-mode with a  $4.7\text{nF}$  capacitor in series with a  $10\text{k}$  resistor between CINT and ground. This value may be reduced to improve transient performance; however, very low values will reduce loop stability. Figures 5 through 10 show a comparison of P-mode vs PI-mode performance.

### Boost Feedback Resistors

As the boost output voltage,  $A_{VDD}$ , is reduced below 12V, the effective voltage feedback in the IC increases the ratio of voltage to current feedback at the summing comparator because  $R_2$  decreases relative to  $R_1$ . To maintain stable operation over the complete current range of the IC, the voltage feedback to the FBB pin should be reduced proportionally, as  $A_{VDD}$  is reduced. This can be accomplished by means of a series resistor-capacitor network ( $R_7$  and  $C_7$ ; Equations 8 and 9) in parallel with  $R_1$ , with a pole frequency ( $f_p$ ) set to approximately 10kHz for  $C_2$  (effective) =  $10\mu$ F and 4kHz for  $C_2$  (effective) =  $30\mu$ F.

$$R_7 = \left( \left( \frac{1}{0.1 \times R_2} \right) - \frac{1}{R_1} \right)^{-1} \quad (\text{EQ. 8})$$

$$C_7 = \frac{1}{2 \times 3.142 \times f_p \times R_7} \quad (\text{EQ. 9})$$

### PI-Mode $C_{INT}$ ( $C_{23}$ ) and $R_{INT}$ ( $R_{10}$ )

The IC is designed to operate with a minimum  $C_{23}$  capacitor of  $4.7\text{nF}$  and a minimum  $C_2$  (effective) =  $10\mu$ F.

Note that, for high voltage  $A_{VDD}$ , the voltage coefficient of ceramic capacitors ( $C_2$ ) reduces their effective capacitance greatly; a  $16\text{V}$ ,  $10\mu$ F ceramic can drop to around  $3\mu$ F at  $15\text{V}$ .

To improve the transient load response of  $A_{VDD}$  in PI-mode, a resistor may be added in series with the  $C_{23}$  capacitor. The larger the resistor, the lower the overshoot, but at the expense of stability of the converter loop, especially at high currents.

With  $L = 10\mu$ H,  $A_{VDD} = 15\text{V}$ , and  $C_{23} = 4.7\text{nF}$ ,  $C_2$  (effective) should have a capacitance of greater than  $10\mu$ F.  $R_{INT}$  ( $R_7$ ) can have values up to  $5\text{k}\Omega$  for  $C_2$  (effective) up to  $20\mu$ F and up to  $10\text{k}$  for  $C_2$  (effective) up to  $30\mu$ F.

Larger values of  $R_{INT}$  ( $R_7$ ) may be possible if maximum  $A_{VDD}$  load currents less than the current limit are used. To ensure  $A_{VDD}$  stability, the IC should be operated at the maximum desired current and then the transient load response of  $A_{VDD}$  should be used to determine the maximum value of  $R_{INT}$ .

### Operation of the DELB Output Function

An open drain DELB output is provided to allow the boost output voltage, developed at  $C_2$  (see “Typical Application Diagram” on page 18), to be delayed via an external switch ( $Q_4$ ) to a time after the  $V_{BOOST}$  supply and negative  $V_{OFF}$  charge pump supply have achieved regulation during the start-up sequence shown in Figures 14 and 16. This then allows the  $A_{VDD}$  and  $V_{ON}$  supplies to start-up from 0V instead of the normal offset voltage of  $V_{IN}-V_{DIODE}$  ( $D_1$ ) if  $Q_4$  were not present.

When DELB is activated by the start-up sequencer, it sinks  $50\mu A$ , allowing a controlled turn-on of  $Q_4$  and charge-up of  $C_9$ .  $C_{16}$  can be used to control the turn-on time of  $Q_4$  to reduce in-rush current into  $C_9$ . The potential divider formed by  $R_9$  and  $R_8$  can be used to limit the  $V_{GS}$  voltage of  $Q_4$  if required by the voltage rating of this device. When the voltage at DELB falls to less than 0.6V, the sink current is increased to  $\sim 1.2mA$  to firmly pull DELB to 0V.

The voltage at DELB is monitored by the fault protection circuit so that if the initial  $50\mu A$  sink current fails to pull DELB below  $\sim 0.6V$  after the start-up sequencing has completed, then a fault condition will be detected and a fault time-out ramp will be initiated on the  $C_{DEL}$  capacitor ( $C_7$ ).

### Operation of the PG Output Function

The PG output consists of an internal pull-up PMOS device to  $V_{IN}$ , to turn off the external  $Q_1$  protection switch, and a current-limited pull-down NMOS device which sinks  $\sim 15\mu A$ , allowing a controlled turn-on of  $Q_1$  gate capacitance.  $C_O$  is used to control how fast  $Q_1$  turns on and limiting inrush current into  $C_1$ . When the voltage at the PG pin falls to less than 0.6V, the PG sink current is increased to  $\sim 1.2mA$  to firmly pull the pin to 0V.

The voltage at PG is monitored by the fault protection circuit so that if the initial  $15\mu A$  sink current fails to pull PG below  $\sim 0.6V$  after the start-up sequencing has completed, then a fault condition will be detected, and a fault time-out ramp will be initiated on the  $C_{DEL}$  capacitor ( $C_7$ ).

### Cascaded MOSFET Application

A 20V N-Channel MOSFET is integrated in the boost regulator. For applications where the output voltage is greater than 20V, an external cascaded MOSFET is needed as shown in Figure 22. The voltage rating of the external MOSFET should be greater than  $V_{BOOST}$ .

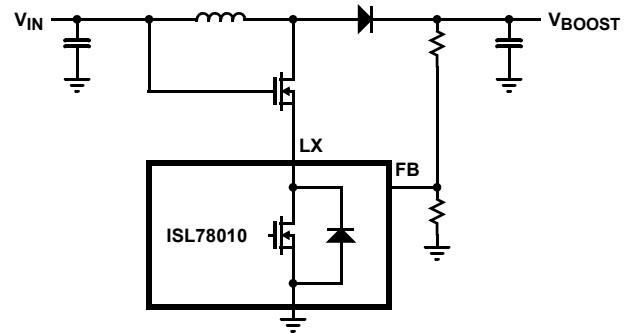


FIGURE 22. CASCADED MOSFET TOPOLOGY FOR HIGH OUTPUT VOLTAGE APPLICATIONS

### Linear-Regulator Controllers ( $V_{ON}$ , $V_{LOGIC}$ , and $V_{OFF}$ )

The ISL78010 includes three independent linear-regulator controllers, in which two are positive output voltage ( $V_{ON}$  and  $V_{LOGIC}$ ) and one is negative. The  $V_{ON}$ ,  $V_{OFF}$ , and  $V_{LOGIC}$  linear-regulator controller functional diagrams are shown in Figures 23, 24, and 25, respectively.

### Calculation of the Linear Regulator Base-Emitter Resistors ( $R_{BL}$ , $R_{BP}$ and $R_{BN}$ )

For the pass transistor of the linear regulator, low frequency gain ( $h_{FE}$ ) and unity gain frequency ( $f_T$ ) are usually specified in the datasheet. The pass transistor adds a pole to the loop transfer function at  $f_p = f_T/h_{FE}$ . Therefore, in order to maintain phase margin at low frequency, the best choice for a pass device is often a high-frequency, low-gain switching transistor. Further improvement can be obtained by adding a base-emitter resistor  $R_{BE}$  ( $R_{BP}$ ,  $R_{BL}$ ,  $R_{BN}$  in the Functional Block Diagrams on page 13), which increase the pole frequency to  $f_p = f_T \cdot (1 + h_{FE} \cdot r_e/R_{BE})/h_{FE}$ , where  $r_e = KT/qI_C$ . Choose the lowest value  $R_{BE}$  in the design as long as there is still enough base current ( $I_B$ ) to support the maximum output current ( $I_C$ ).

For example, if in the  $V_{LOGIC}$  linear regulator, a Fairchild FM549 PNP transistor is used as the external pass transistor ( $Q_5$  in the application diagram), then for a maximum  $V_{LOGIC}$  operating requirement of 500mA, the data sheet indicates  $h_{FE}(\min) = 100$ .

The base-emitter saturation voltage is  $V_{be\_max} = 1.25V$ . Note that this is normally  $V_{be} \sim 0.7V$ ; however, for the  $Q_5$  transistor, an internal Darlington arrangement is used to increase its current gain, giving a “base-emitter” voltage of  $2 \times V_{BE}$ .

Note also that using a high current Darlington PNP transistor for  $Q_5$  requires that  $V_{IN} > V_{LOGIC} + 2V$ . Should a lower input voltage be required, then an ordinary high-gain PNP transistor should be selected for  $Q_5$  to allow a lower collector-emitter saturation voltage.

For the ISL78010, the minimum drive current is as shown in Equation 10:

$$I_{DRVL}(\text{min}) = 8\text{mA} \quad (\text{EQ. 10})$$

The minimum base-emitter resistor,  $R_{BL}$ , can now be calculated as shown in Equation 11:

$$R_{BL}(\text{min}) = V_{BE}(\text{max}) / (I_{DRVL}(\text{min}) - I_C / h_{FE}(\text{min})) = 1.25\text{V} / (8\text{mA} - 500\text{mA} / 100) = 417\Omega \quad (\text{EQ. 11})$$

This is the minimum value that can be used. Choose a convenient value greater than this minimum value; for example,  $500\Omega$ . Larger values may be used to reduce quiescent current; however, regulation may be adversely affected by supply noise if the value of  $R_{BL}$  is too high.

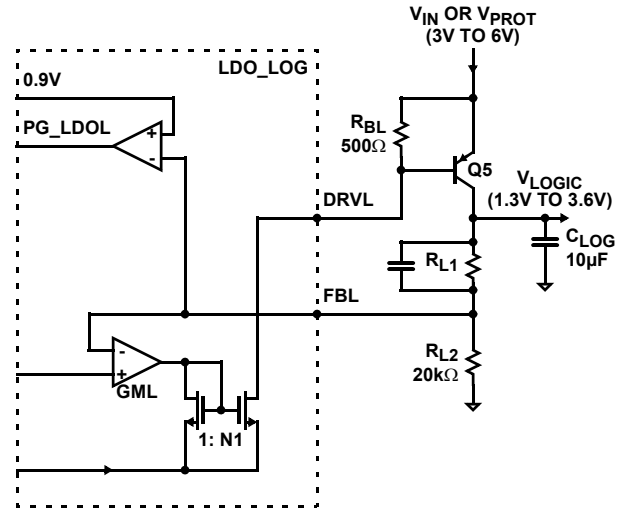


FIGURE 25.  $V_{\text{LOGIC}}$  FUNCTIONAL BLOCK DIAGRAM

The  $V_{\text{ON}}$  power supply is used to power the positive supply of the row driver in the LCD panel. The DC/DC consists of an external diode-capacitor charge pump powered from the inductor (LX) of the boost converter, followed by a low dropout linear regulator (LDO\_ON). The LDO\_ON regulator uses an external PNP transistor as the pass element. The on-board LDO controller is a wide band (>10MHz) transconductance amplifier capable of 4mA drive current, which is sufficient for up to 40mA or more output current under the low dropout condition (forced beta of 10). Typical  $V_{\text{ON}}$  voltage supported by the ISL78010 ranges from +15V to +36V. A fault comparator is also included for monitoring the output voltage. The undervoltage threshold is set at 25% below the 1.2V reference.

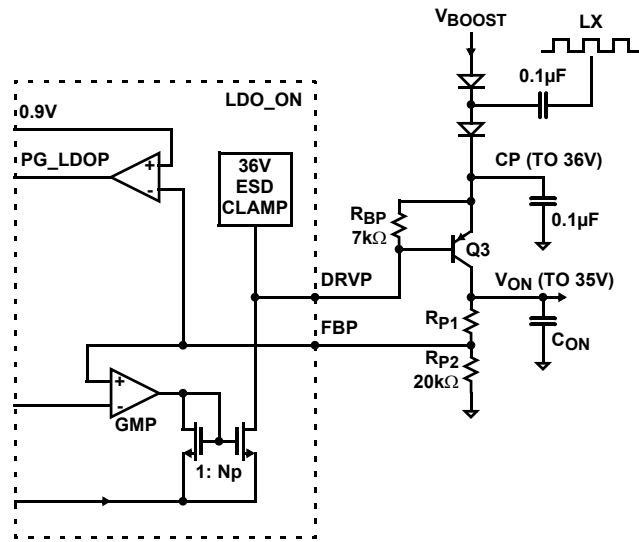


FIGURE 23.  $V_{\text{ON}}$  FUNCTIONAL BLOCK DIAGRAM

The  $V_{\text{OFF}}$  power supply is used to power the negative supply of the row driver in the LCD panel. The DC/DC consists of an external diode-capacitor charge pump powered from the inductor (LX) of the boost converter, followed by a low dropout linear regulator (LDO\_OFF). The LDO\_OFF regulator uses an external NPN transistor as the pass element. The on-board LDO controller is a wide band (>10MHz) transconductance amplifier capable of 4mA drive current, which is sufficient for up to 40mA or more output current under the low dropout condition (forced beta of 10). Typical  $V_{\text{OFF}}$  voltage supported by the ISL78010 ranges from -5V to -20V. A fault comparator is also included for monitoring the output voltage. The undervoltage threshold is set at 200mV above the 0.2V reference level.

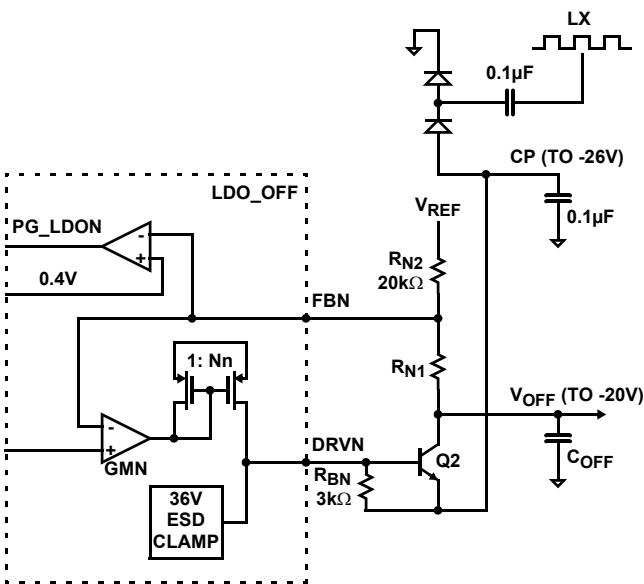


FIGURE 24.  $V_{\text{OFF}}$  FUNCTIONAL BLOCK DIAGRAM

The  $V_{\text{LOGIC}}$  power supply is used to power the logic circuitry within the LCD panel. The DC/DC may be powered directly from the low voltage input, 3.3V or 5.0V, or it may be powered through the fault protection switch. The LDO\_LOGIC regulator uses an external PNP transistor as the pass element. The on-board LDO controller is a wide band (>10MHz) transconductance amplifier capable of 16mA drive current, which is sufficient for up to 160mA or

more output current under the low dropout condition (forced beta of 10). Typical  $V_{\text{LOGIC}}$  voltage supported by the ISL78010 ranges from +1.3V to  $V_{\text{DD}} - 0.2\text{V}$ . A fault comparator is also included for monitoring the output voltage. The undervoltage threshold is set at 25% below the 1.2V reference.

**Set-Up Output Voltage**

As shown in the “Typical Application Diagram” on page 18, the output voltages of  $V_{\text{ON}}$ ,  $V_{\text{OFF}}$ , and  $V_{\text{LOGIC}}$  are as determined by Equations 12, 13 and 14:

$$V_{\text{ON}} = V_{\text{REF}} \times \left( 1 + \frac{R_{12}}{R_{11}} \right) \tag{EQ. 12}$$

$$V_{\text{OFF}} = V_{\text{REFN}} + \frac{R_{22}}{R_{21}} \times (V_{\text{REFN}} - V_{\text{REF}}) \tag{EQ. 13}$$

$$V_{\text{LOGIC}} = V_{\text{REF}} \times \left( 1 + \frac{R_{42}}{R_{41}} \right) \tag{EQ. 14}$$

where  $V_{\text{REF}} = 1.2\text{V}$  and  $V_{\text{REFN}} = 0.2\text{V}$ .

Resistor networks in the order of 250k $\Omega$ , 120k $\Omega$  and 10k $\Omega$  are recommended for  $V_{\text{ON}}$ ,  $V_{\text{OFF}}$  and  $V_{\text{LOGIC}}$ , respectively.

**Charge Pump**

To generate an output voltage higher than  $V_{\text{BOOST}}$ , single or multiple stages of charge pumps are needed. The number of stages is determined by the input and output voltage. Use Equation 15 to calculate positive charge pump stages:

$$N_{\text{POSITIVE}} \geq \frac{V_{\text{OUT}} + V_{\text{CE}} - V_{\text{INPUT}}}{V_{\text{INPUT}} - 2 \times V_{\text{F}}} \tag{EQ. 15}$$

where  $V_{\text{CE}}$  is the dropout voltage of the pass component of the linear regulator. It ranges from 0.3V to 1V depending on the transistor.  $V_{\text{F}}$  is the forward-voltage of the charge pump rectifier diode.

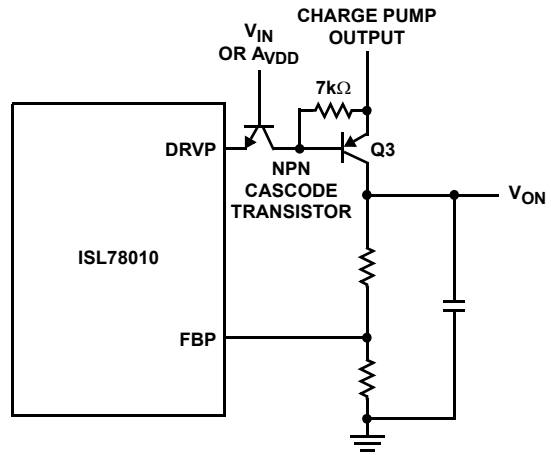
The number of negative charge pump stages is given by Equation 16:

$$N_{\text{NEGATIVE}} \geq \frac{|V_{\text{OUTPUT}}| + V_{\text{CE}}}{V_{\text{INPUT}} - 2 \times V_{\text{F}}} \tag{EQ. 16}$$

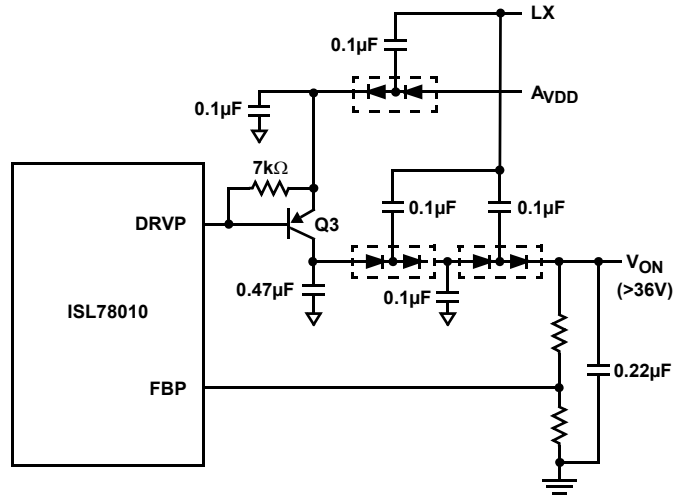
To achieve high efficiency and low material cost, the lowest number of charge pump stages that can meet the above requirements is preferred.

**High Charge Pump Output Voltage (>36V) Applications**

In applications where the charge pump output voltage is over 36V, an external NPN transistor must be inserted between the DRVP pin and the base of pass transistor  $Q_3$  as shown in Figure 26, or the linear regulator can control only one stage charge pump and regulate the final charge pump output as shown in Figure 27.



**FIGURE 26. CASCODE NPN TRANSISTOR CONFIGURATION FOR HIGH CHARGE PUMP OUTPUT VOLTAGE (>36V)**



**FIGURE 27. THE LINEAR REGULATOR CONTROLS ONE STAGE OF CHARGE PUMP**

**Discontinuous/Continuous Boost Operation and its Effect on the Charge Pumps**

The ISL78010  $V_{\text{ON}}$  and  $V_{\text{OFF}}$  architecture uses LX switching edges to drive diode charge pumps from which LDO regulators generate the  $V_{\text{ON}}$  and  $V_{\text{OFF}}$  supplies. Should a regular supply of LX switching edges be interrupted - for example, during discontinuous operation at light  $A_{\text{VDD}}$  boost load currents - it may affect the performance of  $V_{\text{ON}}$  and  $V_{\text{OFF}}$  regulation, depending on their exact loading conditions at the time.

To optimize  $V_{\text{ON}}/V_{\text{OFF}}$  regulation, the boundary of discontinuous/continuous operation of the boost converter can be adjusted, by suitable choice of inductor (given  $V_{\text{IN}}$ ,  $V_{\text{OUT}}$ , switching frequency and the  $A_{\text{VDD}}$  current loading), to be in continuous operation.

Equation 17 gives the boundary between discontinuous and continuous boost operation. Continuous operation (LX switching every clock cycle) requires:

$$\frac{I_{AVDD}(\text{load}) > D \times (1 - D) \times V_{IN}}{2 \times L \times f_{OSC}} \quad (\text{EQ. 17})$$

where the duty cycle,  $D = (V_{VDD} - V_{IN})/V_{VDD}$

For example, with  $V_{IN} = 5V$ ,  $f_{OSC} = 1.0\text{MHz}$  and  $V_{VDD} = 12V$ , continuous operation of the boost converter can be guaranteed as shown in Equations 18, 19, and 20:

$$L = 10\mu\text{H} \text{ and } I_{AVDD} > 61\text{mA} \quad (\text{EQ. 18})$$

$$L = 6.8\mu\text{H} \text{ and } I_{AVDD} > 89\text{mA} \quad (\text{EQ. 19})$$

$$L = 3.3\mu\text{H} \text{ and } I_{AVDD} > 184\text{mA} \quad (\text{EQ. 20})$$

### Charge Pump Output Capacitors

Ceramic capacitors with low ESR are recommended. With ceramic capacitors, the output ripple voltage is dominated by the capacitance value. The capacitance value can be calculated as shown in Equation 21:

$$C_{OUT} \geq \frac{I_{OUT}}{2 \times V_{RIPPLE} \times f_{OSC}} \quad (\text{EQ. 21})$$

where  $f_{OSC}$  is the switching frequency.

### Start-Up Sequence

Figure 28 shows a detailed start-up sequence waveform. For a successful power-up, there should be six peaks at  $V_{CDLY}$ . When a fault is detected, the device will latch off until either EN is toggled or the input supply is recycled.

When the input voltage is higher than 2.5V, an internal current source starts to charge  $C_{CDLY}$  to an upper threshold using a fast ramp followed by a slow ramp. During the initial slow ramp, the device checks whether there is a fault condition. If no fault is found,  $C_{CDLY}$  is discharged after the first peak, and  $V_{REF}$  turns on.

During the second ramp, the device checks the status of  $V_{REF}$  and over-temperature. At the peak of the second ramp, PG output goes low and enables the input protection PMOS  $Q_1$ .  $Q_1$  is a controlled FET used to prevent in-rush current into  $V_{BOOST}$  before  $V_{BOOST}$  is enabled internally. Its rate of turn-on is controlled by  $C_O$ . When a fault is detected, M1 will turn off and disconnect the inductor from  $V_{IN}$ .

With the input protection FET on, NODE1 (see "Typical Application Diagram" on page 18) will rise to  $\sim V_{IN}$ . Initially the boost is not enabled, so  $V_{BOOST}$  rises to  $V_{IN} - V_{DIODE}$  through the output diode. Hence, there is a step at  $V_{BOOST}$  during this part of the start-up sequence. If this step is not desirable, an external P-MOSFET can be used to delay the

output until the boost is enabled internally. The delayed output appears at  $V_{VDD}$ .

$V_{BOOST}$  soft-starts at the beginning of the third ramp. The soft-start ramp depends on the value of the  $C_{DLY}$  capacitor. For  $C_{DLY}$  of 220nF, the soft-start time is  $\sim 2\text{ms}$ .

$V_{REF}$  and  $V_{LOGIC}$  turn on when input voltage ( $V_{DD}$ ) exceeds 2.5V. When a fault is detected, the outputs and the input protection will turn off but  $V_{REF}$  will stay on.

$V_{OFF}$  turns on at the start of the fourth peak. At the fifth peak, the open drain o/p DELB goes low to turn on the external PMOS  $Q_4$  to generate a delayed  $V_{BOOST}$  output.

$V_{ON}$  is enabled at the beginning of the sixth ramp.  $V_{VDD}$ , PG,  $V_{OFF}$ , DELB and  $V_{ON}$  are checked at end of this ramp.

### Fault Protection

During the start-up sequence, prior to BOOST soft-start,  $V_{REF}$  is checked to be within  $\pm 20\%$  of its final value, and the device temperature is checked. If either of these is not within the expected range, the part is disabled until the power is recycled or EN is toggled.

If  $C_{DELAY}$  is shorted low, then the sequence will not start, while if  $C_{DELAY}$  is shorted H, the first down ramp will not occur and the sequence will not complete.

Once the start-up sequence is completed, the chip continuously monitors  $C_{DLY}$ , DELB, FBP, FBL, FBN,  $V_{REF}$ , FBB, and PG, and checks for faults. During this time, the voltage on the  $C_{DLY}$  capacitor remains at 1.15V until either a fault is detected or the EN pin is pulled low.

A fault on  $C_{DELAY}$ ,  $V_{REF}$ , or temperature will shut down the chip immediately. If a fault on any other output is detected,  $C_{DELAY}$  will ramp up linearly with a 5 $\mu\text{A}$  (typical) current to the upper fault threshold (typically 2.4V), at which point the chip is disabled until the power is recycled or EN is toggled. If the fault condition is removed prior to the end of the ramp, the voltage on the  $C_{DLY}$  capacitor returns to 1.15V.

Typical fault thresholds for FBP, FBL, FBN, and FBB are included in the "Electrical Specifications" table beginning on page 2. PG and DELB fault thresholds are typically 0.6V.

$C_{INT}$  has an internal current-limited clamp to keep the voltage within its normal range. If  $C_{INT}$  is shorted low, the boost regulator will attempt to regulate to 0V. If  $C_{INT}$  is shorted H, the regulator switches to P mode.

If any of the regulated outputs ( $V_{BOOST}$ ,  $V_{ON}$ ,  $V_{OFF}$  or  $V_{LOGIC}$ ) are driven above their target levels, the drive circuitry will switch off until the output returns to its expected value.

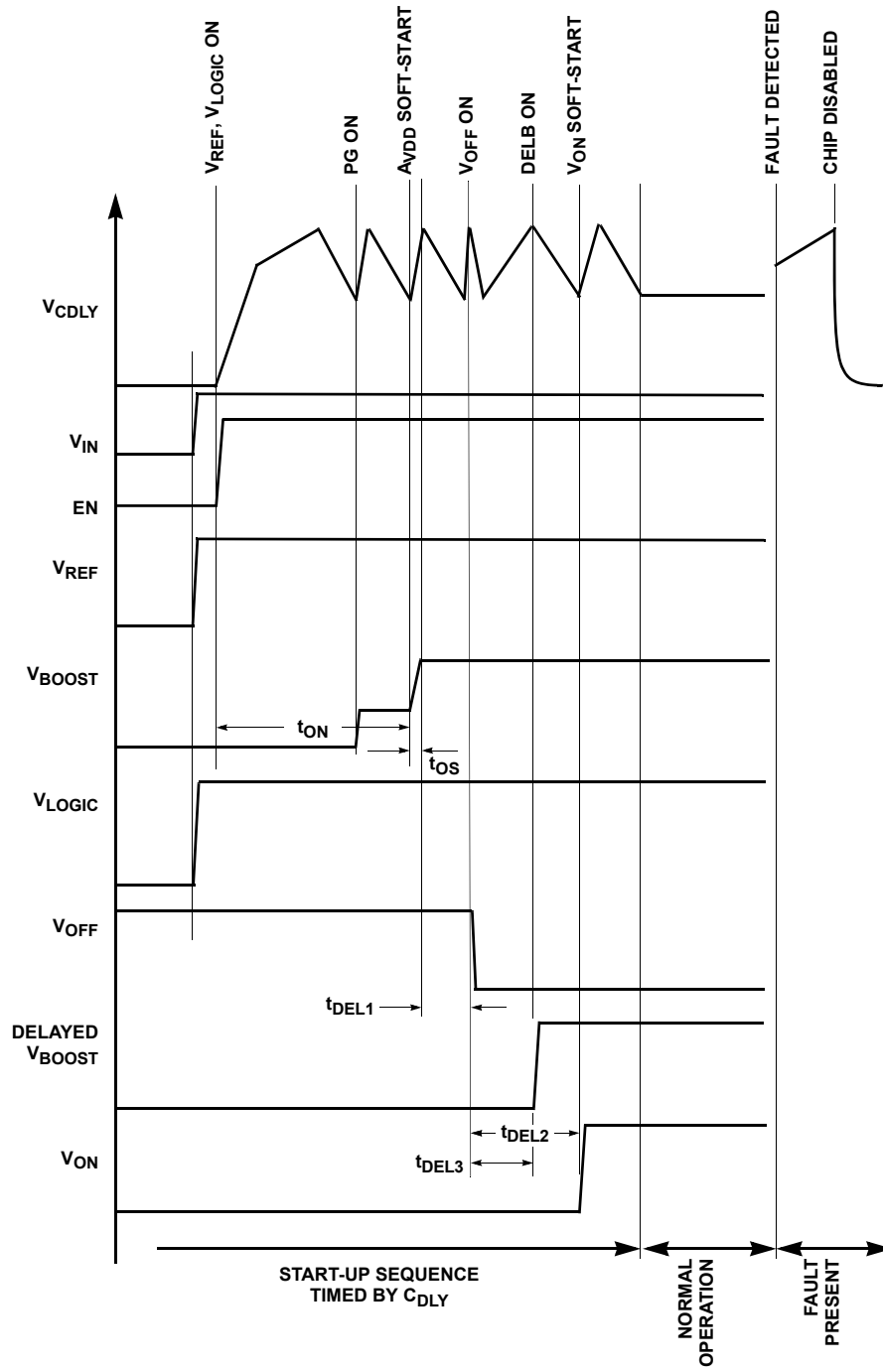


FIGURE 28. START-UP SEQUENCE



If  $V_{BOOST}$  is excessively loaded, the current limit will prevent damage to the chip. While in current limit, the part acts like a current source, and the regulated output will drop. If the output drops below the fault threshold, a ramp will be initiated on  $C_{DELAY}$  and, provided the fault is sustained, the chip will be disabled upon completion of the ramp.

In some circumstances (depending on ambient temperature and thermal design of the board), continuous operation at current limit may result in the over-temperature threshold being exceeded, which will cause the part to disable immediately.

All I/O also has ESD protection, which in many cases will also provide overvoltage protection relative to either ground or VDD. However, these will not generally operate unless absolute maximum ratings are exceeded.

### **Component Selection for Start-Up Sequencing and Fault Protection**

The  $C_{REF}$  capacitor is typically set at 220nF and is required to stabilize the  $V_{REF}$  output. The range of  $C_{REF}$  is from 22nF to 1 $\mu$ F and should not be more than five times the capacitor on  $C_{DEL}$  to ensure correct start-up operation.

The  $C_{DEL}$  capacitor is typically 220nF and has a usable range from 47nF minimum to several microfarads. It is limited only by leakage in the capacitor reaching  $\mu$ A levels.

$C_{DEL}$  should be at least 1/5 of the value of  $C_{REF}$ . Note that with 220nF on  $C_{DEL}$  the fault time-out will typically be 50ms, and the use of a larger or smaller value will vary this time proportionally (e.g., 1 $\mu$ F will give a fault time-out period of typically 230ms).

### **Fault Sequencing**

The ISL78010 has advanced fault detection systems which protect the IC from both adjacent pin shorts during operation and shorts on the output supplies.

A high-quality layout and design of the PCB with respect to grounding and decoupling is necessary to avoid falsely triggering the fault detection scheme, especially during start-up. See "Layout Recommendation" on page 17 and "Component Selection for Start-Up Sequencing and Fault

Protection" on page 17 to avoid problems during initial evaluation and prototype PCB generation.

### **Over-Temperature Protection**

An internal temperature sensor continuously monitors the die temperature. If the die temperature exceeds the thermal trip point of +140°C, the device will shut down.

### **Layout Recommendation**

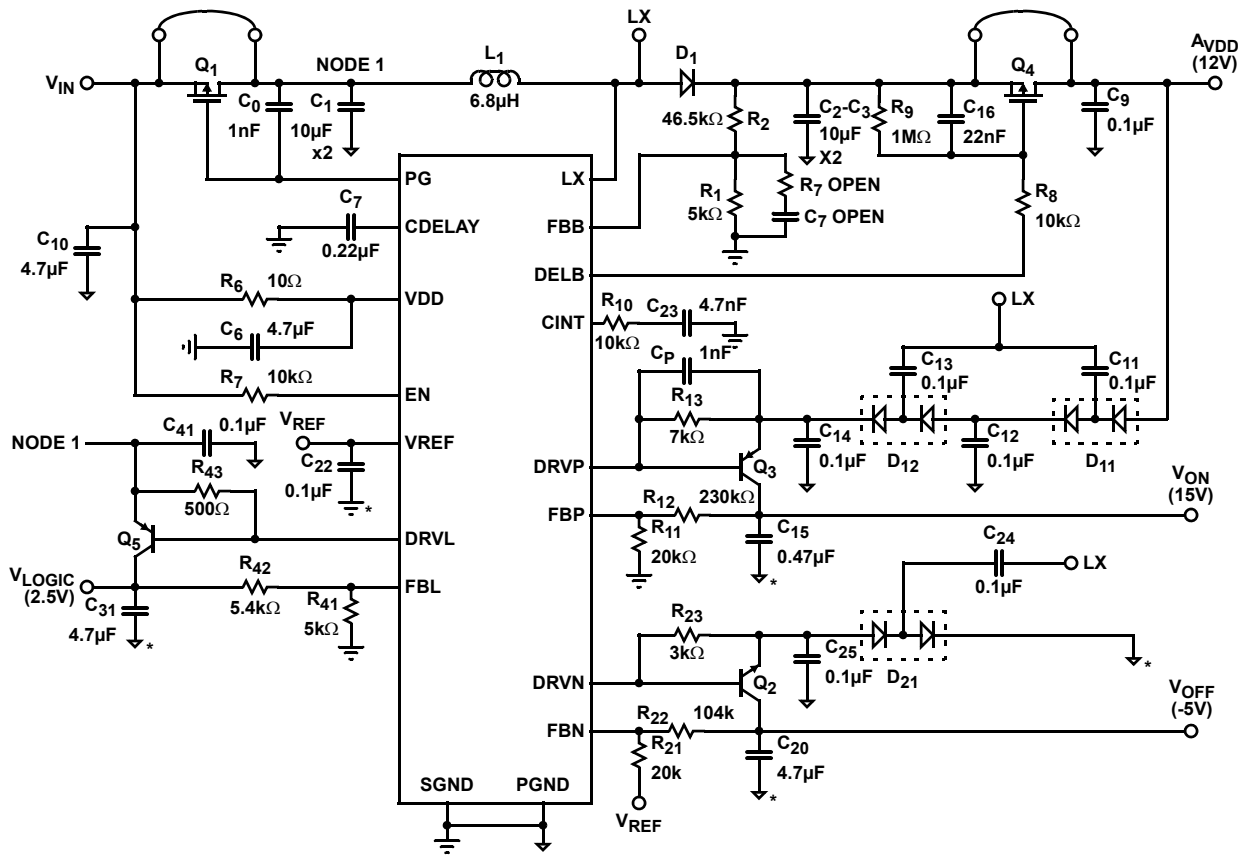
Device performance, including efficiency, output noise, transient response and control loop stability, is dramatically affected by the PCB layout. PCB layout is critical, especially at high switching frequency.

Some general guidelines for layout include:

1. Place the external power components (the input capacitors, output capacitors, boost inductor and output diodes, etc.) in close proximity to the device. Traces to these components should be kept as short and wide as possible to minimize parasitic inductance and resistance.
2. Place  $V_{REF}$  and  $V_{DD}$  bypass capacitors close to the pins.
3. Minimize the length of traces carrying fast signals and high current.
4. All feedback networks should sense the output voltage directly from the point of load, and be as far away from LX node as possible.
5. The power ground (PGND) and signal ground (SGND) pins should be connected at only one point near the main decoupling capacitors.
6. A signal ground plane, separate from the power ground plane, should be used for ground return connections for feedback resistor networks ( $R_1$ ,  $R_{11}$ ,  $R_{41}$ ) and the  $V_{REF}$  capacitor,  $C_{22}$ ; the  $C_{DELAY}$  capacitor,  $C_7$ ; and the integrator capacitor,  $C_{23}$ .
7. Minimize feedback input track lengths to avoid switching noise pickup.
8. Connect all "NC" pins to the ground plane to improve thermal performance and switching noise immunity between pins.

An evaluation board, [ISL78010EVAL1Z](#), is available to illustrate the proper layout implementation. See "Ordering Information" on page 1.

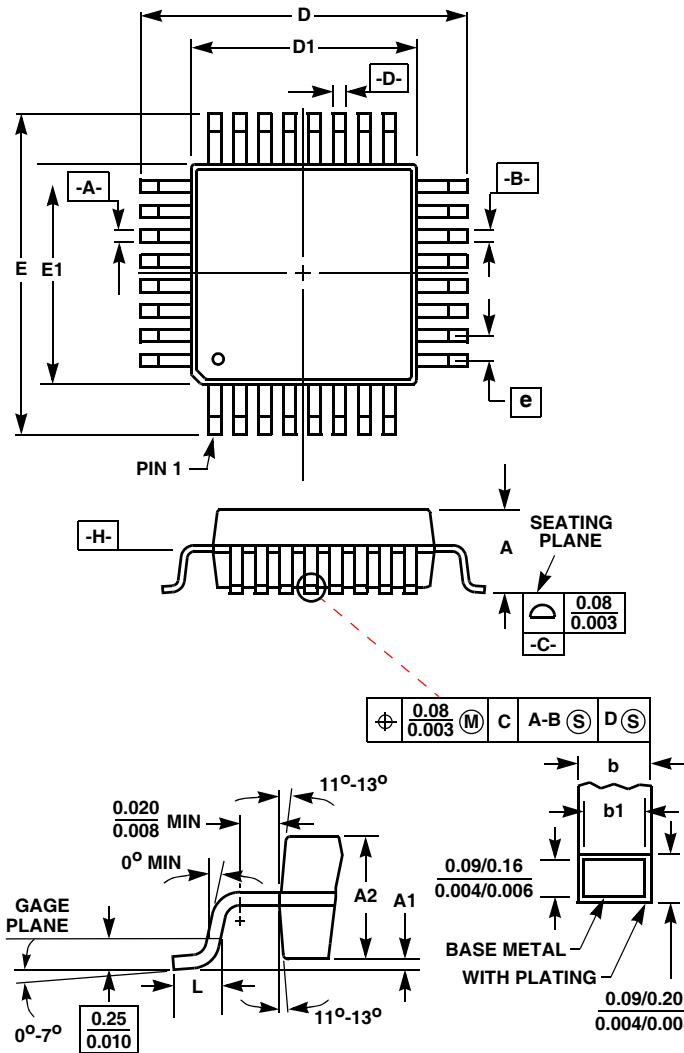
Typical Application Diagram



NOTE: SGND should be connected to PGND at one point only.

Thin Plastic Quad Flatpack Packages (TQFP)

**Q32.5x5 (JEDEC MS-026AAA ISSUE B)  
32 LEAD THIN PLASTIC QUAD FLATPACK PACKAGE**



SYMBOL	MILLIMETERS		NOTES
	MIN	MAX	
A	-	1.20	-
A1	0.05	0.15	-
A2	0.95	1.05	-
b	0.17	0.27	6
b1	0.17	0.23	-
D	6.90	7.10	3
D1	4.90	5.10	4, 5
E	6.90	7.10	3
E1	4.90	5.10	4, 5
L	0.45	0.75	-
N	32		7
e	0.50 BSC		-

Rev. 0 2/07

NOTES:

1. Controlling dimension: MILLIMETER. Converted inch dimensions are not necessarily exact.
2. All dimensions and tolerances per ANSI Y14.5M-1982.
3. Dimensions D and E to be determined at seating plane **-C-**.
4. Dimensions D1 and E1 to be determined at datum plane **-H-**.
5. Dimensions D1 and E1 do not include mold protrusion. Allowable protrusion is 0.25mm (0.010 inch) per side.
6. Dimension b does not include dambar protrusion. Allowable dambar protrusion shall not cause the lead width to exceed the maximum b dimension by more than 0.08mm (0.003 inch).
7. "N" is the number of terminal positions.

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